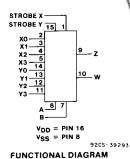


RECOMMENDED FOR NEW DESIGNS

# CD4529B Types



## CMOS Dual 4-Channel Analog Data Selector

High-Voltage Types (20-Volt Rating) Features:

- Wide range of digital and analog signal levels: Digital: 3 to 20 V
- Analog: 0 to 20 V<sub>p-p</sub>
   Low ON-state resistance: 120 Ω typ. at 15 V
- Break-Before-Make switching eliminates channel overlap
- 100% tested for quiescent current at 20 V
- 5-V, 10-V, and 15-V parametric ratings
- Maximum input current of 1 μA at 18 V over full package-temperature range;
   100 nA at 18 V and 25° C
- Noise margin (full package-temperature range) = 1 V at V<sub>DD</sub>=5 V 2 V at V<sub>DD</sub>=10 V 2.5 V at V<sub>DD</sub>=15 V
- Meets all requirements of JEDEC Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

■ CD4529B CMOS dual 4-channel analog data selector consists of digitally controlled analog switches having low on-impedance and very low off-leakage current. The CD4529B is bidirectional and can also be used in digital applications. By tying Z and W together the device can be used as a single 8-channel analog data selector.

The CD4529B device is supplied in 16-lead ceramic dual-in-line packages (D and F suffixes), 16-lead plastic dual-in-line package (E suffix), and in chip form (H suffix).

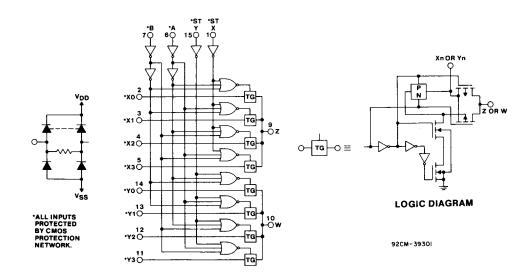


Fig. 1 - Schematic and logic diagram.

 MAXIMUM RATINGS, Absolute-Maximum Values:

 DC SUPPLY-VOLTAGE RANGE, (VDD)
 -0.5V to +20V

 Voltages referenced to Vss Terminal)
 -0.5V to VDD +0.5V

 INPUT VOLTAGE RANGE, ALL INPUTS
 -0.5V to VDD +0.5V

 DC INPUT CURRENT, ANY ONE INPUT
 ±10mA

 POWER DISSIPATION PER PACKAGE (PD):
 500mW

 For TA = -559C to +100°C
 Derate Linearity at 12mW/°C to 200mW

 DEVICE DISSIPATION PER OUTPUT TRANSISTOR
 100mW

 FOR TA = FULL PACKAGE-TEMPERATURE RANGE (All Package Types)
 100mW

 OPERATING-TEMPERATURE RANGE (Ta)
 -55°C to +125°C

 STORAGE TEMPERATURE RANGE (Tstg)
 -65°C to +150°C

 LEAD TEMPERATURE (DURING SOLDERING):
 At distance 1/16 ± 1/32 inch (1.59 ± 0.79mm) from case for 10s max
 +265°C

### RECOMMENDED OPERATING CONDITIONS at TA = 25°C (Unless Otherwise Specified)

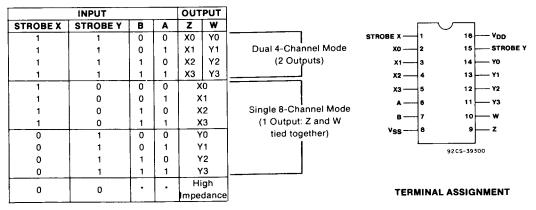
For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges. Values shown apply to all types except as noted.

CHARACTERISTIC	VDD	Min.	Max.	UNITS
Supply-Voltage Range (T <sub>A</sub> = Full Package-Temperature Range)	_	3	18	V
Multiplexer Switch Input Current Capability*	_		25	mA
Output Load Resistance		100		Ω

In certain applications, the external load-resistor current may include both Voo and signal-line components. To avoid drawing Voo current when switch current flows into the transmission gate inputs, the voltage drop across the bidirectional switch

must not exceed 0.8 volt (calculated from  $R_{ON}$  values shown in Electrical Characteristics Chart). No  $V_{OD}$  current will flow through  $R_L$  if the switch current flows into terminals 9 and 10 (Z and W, respectively).

#### TRUTH TABLE



<sup>\* =</sup> Don't Care

### **ELECTRICAL CHARACTERISTICS**

CHARACTERISTIC	CONDITIONS		LIMITS AT INDICATED TEMPERATURES (°C)							UNITS	
	Vss VDD		V <sub>DD</sub>	D -55 -40 +8			+125	+25			1
		(V)	(V)	-33	-40	703	+ 125	Min.	Тур.	Max.	<u> </u>
SIGNAL INPUTS (V <sub>IN</sub> ) AND OUT	PUTS (VOUT)										
			5	5	5	150	150	-	0.04	5	μΑ
Quiescent Device			10	10	10	300	300		0.04	10	
Current, IDD Max.		-	15	20	20	600	600		0.04	20	
			20	100	100		3000	<u> </u>	0.08	100	
		-5	5	400	410	560	640		240	480	l
On-State Resistance		-7.5	7.5	240	250	350	400		135	270	
$0 \le V_{IN} \le V_{DD}$		0	5	800	850	1	1300		470	1050	Ω
ron Max.		0	10	400	410	560	640		240	480	]
		0	15	250	250	350	400	_	135	270	L
Change in On-State		0	5				<u> </u>	1=	15		1 _
Resistance (Between Any		0	10		_	_	<u> </u>		10		Ω
Two Channels) $\Delta r_{ON}$		0	15			_	<u> </u>	_	5		
OFF Channel Leakage Current: Any Channel OFF Max. or All Channels OFF (Common OUT/IN) Max.		0	18	±1	00*	±1	000*	_	±0.01	±100*	nA
Capacitance:											
Input, C <sub>IN</sub>		1		_	_		<u> </u>	<u> </u>	5		_
Output, Cout		-5	5	_		-	-		18	_	pF
Feedthrough, Clos				<u> </u>	-	_			0.2		ļ
Propagation Delay Time (Signal Input to Output) (t <sub>PHL</sub> ,t <sub>PLH</sub> )	V <sub>SS</sub> =0, R <sub>L</sub> =1 kΩ, C <sub>L</sub> =50 pF, V <sub>IN</sub> =V <sub>DD</sub> -V <sub>SS</sub> (Square Wave), t <sub>r</sub> ,t <sub>r</sub> =20 ns	0	5 10 15	  -  -		=	_	  -  -  -	20 10 8	40 20 15	ns
CONTROL (ADDRESS OR STRO	BE) VC						-				
	V -V	T	5	1.5 —		1.5					
Input Low Voltage, V <sub>ILC</sub> Max.	VIN=VDD,		10			3				3	]
	R∟≂1 kΩ to Vss		15			4			_	4	] v
	$f_{is}$ < 2 $\mu$ A		5		3	1.5		3.5	_	[	]
Input High Voltage, V <sub>IHC</sub> Min.	on all OFF		10	7		7			_	_	
	Channels	1	15			11		11			]
Input Current, I <sub>IN</sub> Max.	V <sub>IN</sub> =0, 18		18	±0.1	±0.1	±1	±1		±10 <sup>-5</sup>	±0.1	μA
Propagation Delay Time: Control to Signal OUT (tehl., telh)	t,,t <sub>r</sub> =20 ns, R <sub>L</sub> =1 kΩ, C <sub>L</sub> =50 pF, V <sub>IN</sub> =V <sub>DD</sub> -Vss (Square Wave)		5 10 15	_ 	_ _ _	  -  -	  -  -  -	  -  -	200 80 60	400 160 120	ns
Input Capacitance, C <sub>IN</sub> (Any Address or Strobe Input)	· · · · · · · · · · · · · · · · · · ·		-	-	-	-	-	-	5	7.5	pF

<sup>\*</sup>Determined by minimum feasible leakage measurement for automatic testing.

### ELECTRICAL CHARACTERISTICS (Cont'd) at TA = 25°C

	TEST CONDITIONS	•	LIMITS			UNITS			
CHARACTERISTIC		VDD	Min.	Тур.	Max.	UNITS			
		5	_	5	_				
Crosstalk Voltage, Control to Output	$R_L = 1 k\Omega$ , $C_L = 50 pF$ , $R_{OUT} = 10 k\Omega$	10		5	—	mV			
		15	_	5					
Maximum Control Input Pulse Frequency		5		5	—	1			
	$R_L = 1 \text{ k}\Omega$ , $C_L = 50 \text{ pF}$	10	-	10		MHz			
		15	_	12					
Noise Voltage		5	-	24	-				
	f = 100 Hz	10	-	25	_				
		15		30	<u> </u>	nV_			
		5	-	12	<b>—</b>	√cycle			
	f = 100 kHz	10	_	12	_				
		15	<u> </u>	15		_			
Sine Wave Distortion	V <sub>IN</sub> = 1.77 V dc (RMS) centered								
	at 0 V dc, $R_L$ = 10 k $\Omega$ , f = 1 kHz,	5	_	0.36	_	%			
	V <sub>SS</sub> = -5 V		ļ	ļ	ļ	L			
	V <sub>IN</sub> = 1.77 V dc (RMS) centered			ŀ					
Insertion Loss	at 0 V dc, f = 1 MHz, V <sub>ss</sub> = -5 V,	İ			1				
	ILOSS = 20 log10 Vout								
	V <sub>IN</sub>								
	R = 1 kΩ	5	-	2					
	R = 10 kΩ		-	0.8	-	-   <sub>dB</sub>			
	R = 100 kΩ		-	0.25	5   —				
	R = 1 MΩ		↓-	0.01		ļ <u> </u>			
	V <sub>IN</sub> = 1.77 V dc (RMS) centered	1			l				
Bandwidth (-3 dB)	at 0 V dc, V <sub>ss</sub> = -5 V	1							
	R = 1 kΩ	5	-	35	-				
	R = 10 kΩ		-	28	-	MHz			
					-	]			
	R = 1 MΩ	ļ	<del>  -</del>	26	<del>  _</del> _				
Feedthrough and Crosstalk	V <sub>ss</sub> = -5 V				1				
	$\frac{20 \log_{10} \frac{V_{OUT}}{V_{IN}}}{V_{IN}} = -50 \text{ dB}$								
	R = 1 kΩ	5	-	850	-				
	$R = 10 \text{ k}\Omega$				_	kHz			
	R = 100 kΩ		_	12	_	-   KMZ			
	R = 1 MΩ		_	1.5	_				

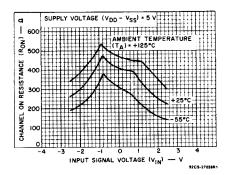


Fig. 2 - Typical channel ON resistance vs. input signal voltage.

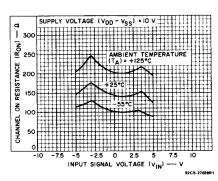


Fig. 3 - Typical channel ON resistance vs., input signal voltage.

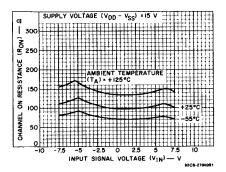


Fig. 4 - Typical channel ON resistance vs. input signal voltage.

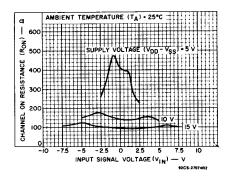


Fig. 5 - Typical channel ON resistance vs. input signal voltage.

#### TEST CIRCUITS

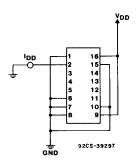


Fig. 6 - OFF channel leakage currentany channel OFF.

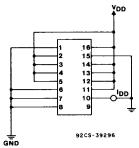


Fig. 7 - OFF channel leakage current, all channels OFF.

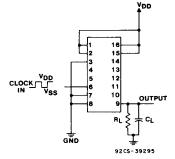


Fig. 8 - Propagation delay address input to signal output.

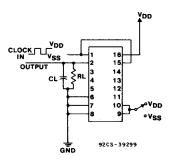


Fig. 9 - Propagation delay-strobe input to signal output.

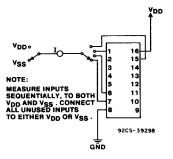


Fig. 10 - Quiescent device current.

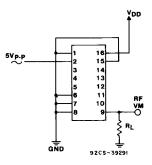


Fig. 11 - Feedthrough.

#### **TEST CIRCUITS (Cont'd)**

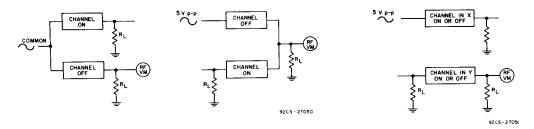


Fig. 12 - Crosstalk between any two channels.

Fig. 13 - Crosstalk between sections.

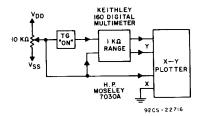
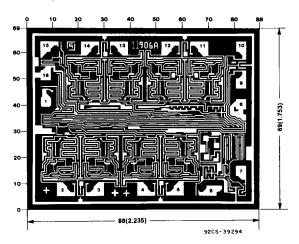


Fig. 14 - Channel ON resistance measurement circuit.



Dimensions and pad layout for CD4529B.

Dimensions in parenthese are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mills ( $10^{-3}$  inch).